

Search Notes

Application/Control No.

10/777,922

Examiner

Tri T. Ton

Applicant(s)/Patent under
Reexamination

YANG ET AL.

Art Unit

2877

SEARCHED


Class	Subclass	Date	Examiner
356	237.3	3/10/2006	TT
356	237.2	3/14/2006	TT
356	237.4	3/14/2006	TT
356	237.5	3/14/2006	TT
356	239.1	3/14/2006	TT
356	239.3	3/14/2006	TT
250	559.4	3/14/2006	TT
250	559.41	3/14/2006	TT
250	559.42	3/14/2006	TT
250	559.45	3/14/2006	TT
356	237.1	6/1/2006	TT

INTERFERENCE SEARCHED


Class	Subclass	Date	Examiner
356	237.100	6/1/2006	TT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
6215551 and 5179422 citation	3/15/2006	TT
inventers' name and company's name	3/15/2006	TT
key word	3/10/2006	TT
consulting with PE Hoa Pham	3/15/2006	TT
IEEE Xplore	6/1/2006	TT


Search Notes 	Application/Control No. 10777922	Applicant(s)/Patent Under Reexamination YANG ET AL.
	Examiner Ton, Tri T	Art Unit 2877

Notes	Date	Examiner
IEEE Xplore	06/01/2006	tt
U.S. Patent and Trademark Office		Part of Paper No.: 06022006

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356	237.100	06/01/2006	tt

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<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10777922</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>YANG ET AL.</p>
	<p>Examiner</p> <p>Ton, Tri T</p>	<p>Art Unit</p> <p>2877</p>

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356	237.1	06/01/2006	tt

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